

**Notice of References Cited**

Application/Control No.

10/577,325

Applicant(s)/Patent Under

Reexamination

NAKAMURA ET AL.

Examiner

MATTHEW W. SUCH

Art Unit

2891

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,224,787	05-2001	Hanna et al.	252/299.3
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Klauk, H., et al. "Contact Resistance in Organic Thin Film Transistors." SOLID-STATE ELECTRONICS, Vol. 47 (2003): pp. 297-301.
	V	
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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